Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/617,285	YAKURA ET AL.
Examiner	Art Unit
Shih-wen Hsieh	2861

Shih-wen Hsieh

	SEARCHED				
Class	Subclass	Date	Examiner		
updated	updated	5/4/2005	///wat SWH		
					
			-		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
347	29,30	5/4/2005	SWH
347	33,35	5/4/2005	SWH

(INCLUDING SEAR	CH STRATEGY	SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR			
		 			
	:				
	· ·				